

Inspection Criteria (KIBAN)

P/N

TCSCA1465

I/C#

AQ-98-DB-0169-1

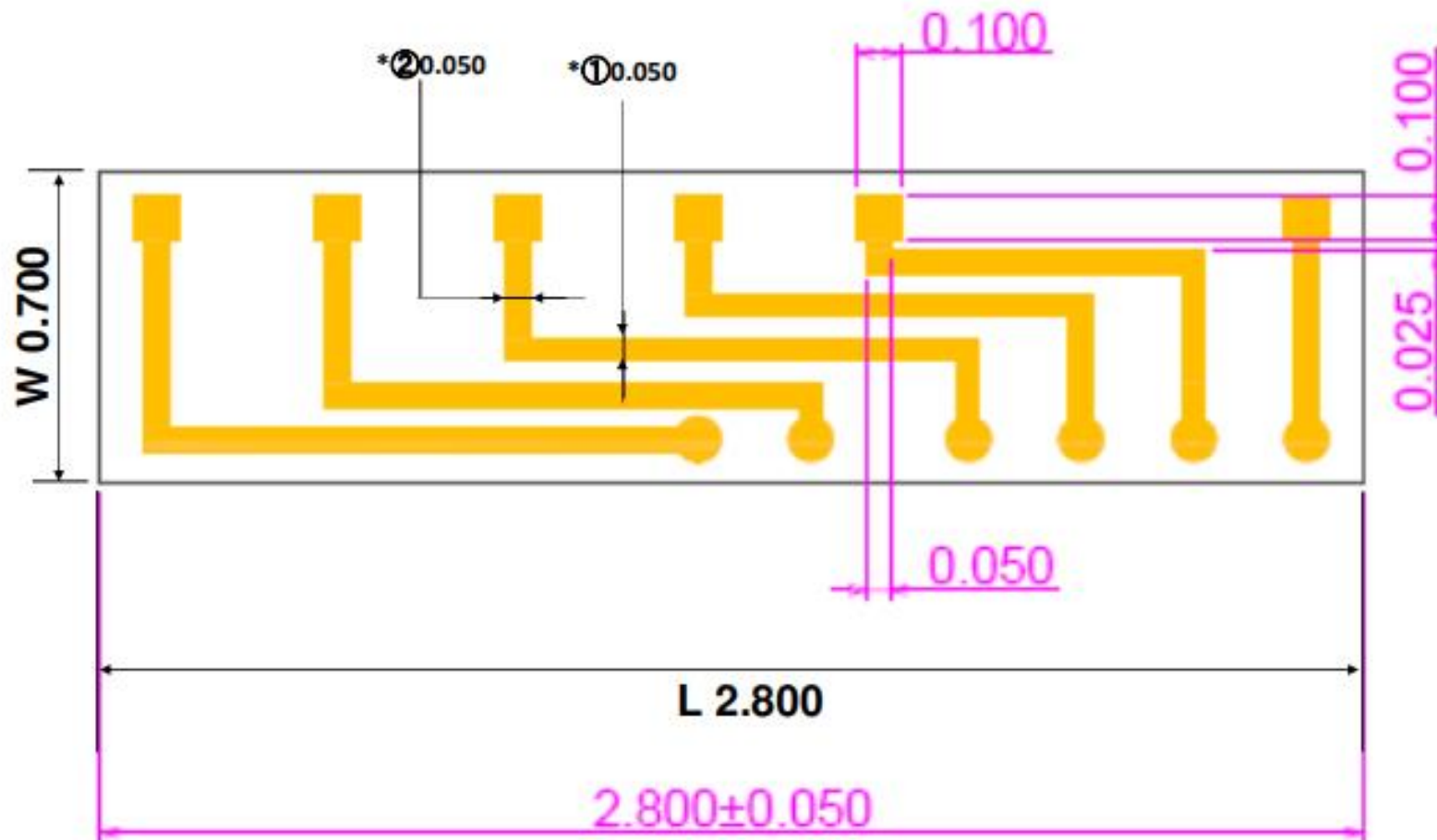
Date:

2023/12/20

[Mechanical Dimensions]
& [Measurement/Test Location]

P1/2

A-Face



B-Face: No Metallization



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General Information

Test/Measurement condition

for SWR or First Article

Customer	NIHONDENKEI		
P/N	TCSCA1465		
Ceramic	CoorsTek SS996 2" t=0.254mm		
Surface Finish	Polished	/	Polished
Dim. (T)	0.254	± 0.013	mm
Dim. (L)	2.800	± 0.050	mm
Dim. (W)	0.700	± 0.050	mm
◆ Metallization(A)	2.0	um	Min
◆ Metallization(B)	N/A	um	Min
Au Pattern Tol.	±	0.030	mm
AuSn-t (x)	N/A	um	Min
AuSn-t (x)	N/A	um	Min
AuSn Pattern Tol.	±	N/A	mm
Sheet R	N/A		Ω/sq
R Value	N/A		Ω
R-tol	N/A		%
Conduction			Ω
IR-pp	N/A	@	V
Angle meas.	N/A		
—			
Chip Tray #	H20-059157-62C02		

Test Item and sample Q'ty		Special Notes			
Knife check	N/A	—			
Visual Spec	Planar	AQ-04-DG-1434-latest			
Out Line(T)	3pc/wf	—			
Out Line(L/W)	3pc/wf	—			
Pattern meas.	3pc/wf	—			
Wire Bd	N/A	—			
Tape Test	N/A	—			
HRT	N/A	—			
Die Shear	N/A	—			
Conduction	N/A	—			
Resistance	N/A	—			
Angle	N/A	—			
IR-pp	N/A	—			
AuSn Melting	N/A	—			
In-Process measurement data confirmation		A-Face	B-Face	C-Face	D-Face
Au-t		YES	—	—	—
AuSn-t		—	—	—	—
AuSn Composition		—	—	—	—

CONT

FOR PH

Rev:
Issued to:

EXT E

DOCUME

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D

REC

◆Metallization Layer Construction

Metalize

■ Ti(0.06)-Pt(0.15)-Au(2.0Min.) (um)



Revision History

Rev.1 2023/12/20 First Issue.

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APPROVED

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